Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
09/924,310	HAN ET AL.
Examiner	Art Unit
Md S. Elahee	2614

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Class	Subclass	Date	Examiner
704	270	11/19/2006	ME
455	563, 564	11/20/2006	ME

INT	ERFERENC	E SEARCH	IED
Class	Subclass	Date	Examiner
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11/20/2006	EXMR ME
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